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Attorney Docket No.: 34592/US Express Mail Label No.: EV 423 775 549 US

Confirmation No.: 2328

Group Art Unit: 2829

Examiner: Evan T. Pert

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of:

Fredrick W. Crist et al.

Appln. No.: 09/676,292

Filed: September 28, 2000

For: METHOD AND APPARATUS FOR REMOTELY

TESTING SEMICONDUCTORS

Mail Stop Amendment Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

> SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT Under 37 C.F.R. § 1.97(c)(2) and § 1.98

Sir:

The Examiner is requested to consider the references noted on the enclosed Form PTO-1449 during examination of the above-identified patent application. The references are submitted for the Examiner's consideration and are submitted pursuant to the duty of disclosure under 37 C.F.R. § 1.56. In submitting the references, no representation is made or implied that the references are or are not material to the examination of the application. The Examiner is encouraged to make his or her own determination of materiality. Copies of the cited documents are provided.

Pursuant to 37 C.F.R. §1.97(c)(1) and § 1.97(e)(1), the references cited on the attached PTO-1449 were previously cited to the Office on July 12, 2004, in an Information Disclosure Statement and Information Disclosure Statement by Applicant Form PTO-1449 with only English translations of the Abstracts. Since that disclosure, we have received computergenerated English translations of the references from the Japanese Patent Office website.

10/08/2004 SSITHIB1 00000039 09676292 01 FC:1806 180.00 OP

Application No.: 09/676,292 Attorney Docket No. 34592/US

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The references were cited in an Office action dated April 22, 2004, of corresponding Japanese patent application No. 2001-287506.

Japanese publication Nos. 06-120316; 11-015520; 10-256109; and 2000-077290 are not in the English language. Under 37 C.F.R. § 1.98(a)(3), any information disclosure statement filed under 37 C.F.R. § 1.97 shall include a concise explanation of the relevance, as it is presently understood by the individual designated in 37 C.F.R. § 1.56(c) most knowledgeable about the content of the information, of each patent, publication or other information listed that is not in the English language. The complete computer-generated English translations of the applications (from the Japanese Patent Office website) are attached to each original Japanese language reference and included herewith to satisfy the requirement for a concise explanation of relevance under 37 C.F.R. § 1.98(a)(3).

Pursuant to 37 C.F.R. § 1.97(c)(2), a check for the \$180.00 fee is enclosed. If any additional fees are deemed necessary, such fees may be charged to Deposit Account No. 04-1415.

If the examiner has any questions, please contact the undersigned attorney.

Dated: 5 Oct 2004

Respectfully submitted,

Gregory P. Durbin, Reg. No. 42,503 DORSEY & WHITNEY LLP 370 Seventeenth Street, Suite 4700

Denver, CO 80202-5647 Tel.: (303) 629-3400

Fax: (303) 629-3450

USPTO Customer No. 20686

Enclosures



EV423775549US

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CERTIFICATE OF MAILING BY EXPRESS MAIL

Mail Stop Amendment Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

The undersigned hereby certifies that the following documents:

- Supplemental Information Disclosure Statement Under 37 C.F.R. § 1.97(c)(2) 1. and § 1.98;
- 2. Information Disclosure Statement by Applicant (Form PTO-1449);
- Four (4) references, including complete computer-generated 3. English translations from the Japanese Patent Office website attached to each original Japanese language reference;
- 4. Check for \$180.00;
- Certificate of Mailing by Express Mail; and 5.
- 6. Return Card,

relating to the above application, were deposited as "Express Mail," under 37 C.F.R. § 1.10, Mailing Label No. EV 423 775 549 US with the United States Postal Service, addressed to Mail Stop Amendment, Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on this 5 day of October 2004.

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FORM PTO-1445 U.S. DEPARTME, T OF COMMERCE	ATTY. DOCKET NO.	APPLN. NO.	
(Modified) REPENT AND TO DEMARK OFFICE	34592/US	09/676,292	
INFORMATION DISCLOSURE	APPLICANT: Fredrick W. Crist et al.		
STATEMENT BY APPLICANT	Freurick W. Crist et al.		
(Use several sheets if necessary)	FILING DATE	GROUP	
	September 28, 2000	2829	

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	PATENT NUMBER	ISSUE DATE	PATENTEE	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
				,		
					-	

FOREIGN PATENT OR PUBLISHED FOREIGN PATENT APPLICATION

NUMBER	DATE					
	DATE	COUNTRY	CLASS	SUBCLASS	YES	NO
*06-120316	04/28/1994	JP			х	
*10-256109	09/25/1998	JР			х	
*11-015520	01/22/1999	JР			Х	
*2000-077290	03/14/2000	JР			х	
	*10-256109 *11-015520	*10-256109 09/25/1998 *11-015520 01/22/1999	*10-256109 09/25/1998 JP *11-015520 01/22/1999 JP	*10-256109 09/25/1998 JP *11-015520 01/22/1999 JP	*10-256109 09/25/1998 JP *11-015520 01/22/1999 JP	*10-256109 09/25/1998 JP x *11-015520 01/22/1999 JP x

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)					
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EXAMINER	DATE CONSIDERED				

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

^{*}Previously cited to the Office on July 12, 2004, with only English translations of the Abstracts. Original and translated copies included.